

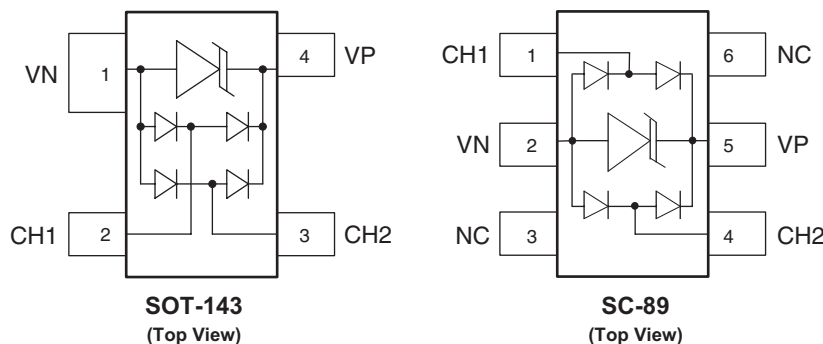
## Ordering Information

Part Number	Ambient Temperature Range	Package	Environmental
AOZ8001KI	-40°C to +85°C	SC-89	RoHS Compliant
AOZ8001JI		SOT-143	



All AOS Products are offering in packaging with Pb-free plating and compliant to RoHS standards.  
Please visit [www.aosmd.com/web/rohs\\_compliant.jsp](http://www.aosmd.com/web/rohs_compliant.jsp) for additional information.

## Pin Configuration



## Absolute Maximum Ratings

Exceeding the Absolute Maximum ratings may damage the device.

Parameter	Rating
VP – VN	6V
Peak Pulse Current ( $I_{PP}$ ), $t_p = 8/20\mu s$	5A
Peak Power Dissipation (TBD @ 25°C) SOT-143 SC-89	TBD TBD
Storage Temperature ( $T_S$ )	-65°C to +150°C
ESD Rating per IEC61000-4-2, Contact <sup>(1)</sup>	±8kV
ESD Rating per IEC61000-4-2, Air <sup>(1)</sup>	±15kV
ESD Rating per Human Body Model <sup>(2)</sup>	±15kV

### Notes:

- IEC 61000-4-2 discharge with  $C_{Discharge} = 150pF$ ,  $R_{Discharge} = 330\Omega$ .
- Human Body Discharge per MIL-STD-883, Method 3015  $C_{Discharge} = 100pF$ ,  $R_{Discharge} = 1.5k\Omega$ .

## Maximum Operating Ratings

Parameter	Rating
Junction Temperature ( $T_J$ )	-40°C to +85°C

## Electrical Characteristics

$T_A = 25^\circ\text{C}$  unless otherwise specified. Specifications in **BOLD** indicate a temperature range of  $-40^\circ\text{C}$  to  $+85^\circ\text{C}$ .

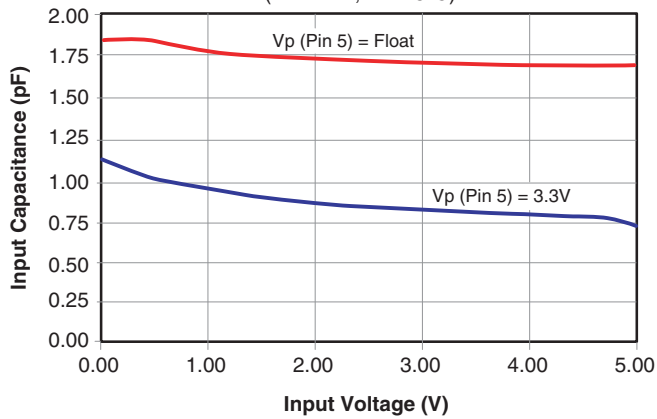
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Units		
V <sub>RWM</sub>	Reverse Working Voltage	Between pin 5 and 2 <sup>(3)</sup>			5.5	V		
V <sub>BR</sub>	Reverse Breakdown Voltage	I <sub>T</sub> = 1mA, between pins 5 and 2 <sup>(4)</sup>	6.6			V		
I <sub>R</sub>	Reverse Leakage Current	V <sub>RWM</sub> = 5V, between pins 5 and 2			0.1	μA		
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 15mA	0.70	0.85	1	V		
V <sub>CL</sub>	Channel Clamp Voltage	I <sub>PP</sub> = 1A, tp = 100ns, any I/O pin to Ground <sup>(5)(7)</sup>			9.75	V		
	Positive Transients				-1.52	V		
	Negative Transient							
	Channel Clamp Voltage	I <sub>PP</sub> = 5A, tp = 100ns, any I/O pin to Ground <sup>(5)(7)</sup>					10.42	V
	Positive Transients						-2.94	V
	Negative Transient							
C <sub>j</sub>	Junction Capacitance	V <sub>R</sub> = 0V, f = 1MHz, any I/O pin to Ground <sup>(5)</sup>		1.85	1.94	pF		
		V <sub>R</sub> = 0V, f = 1MHz, between I/O pins <sup>(5)</sup>		0.9	0.94	pF		
		V <sub>R</sub> = 0V, f = 1MHz, any I/O pin to Ground <sup>(6)</sup>		1.0	1.17	pF		
ΔC <sub>j</sub>	Channel Input Capacitance Matching	V <sub>R</sub> = 0V, f = 1MHz, between I/O pins <sup>(5)</sup>			0.03	pF		

### Notes:

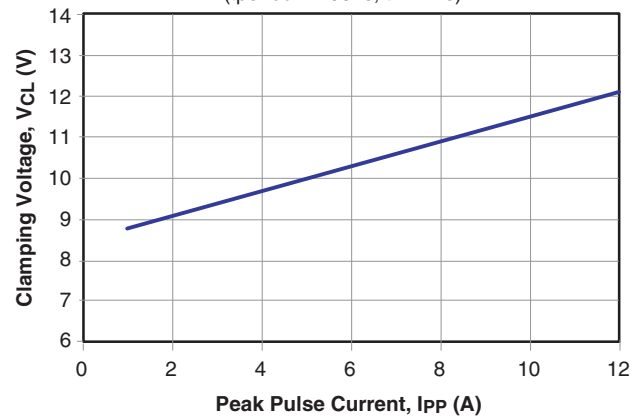
- The working peak reverse voltage,  $V_{RWM}$ , should be equal to or greater than the DC or continuous peak operating voltage level.
- $V_{BR}$  is measured at the pulse test current  $I_T$ .
- Measurements performed with no external capacitor on  $V_P$  (pin 5 floating).
- Measurements performed with  $V_P$  biased to 3.3 Volts (pin 5 @ 3.3V).
- Measurements performed using a 100ns Transmission Line Pulse (TLP) system.

## Typical Performance Characteristics

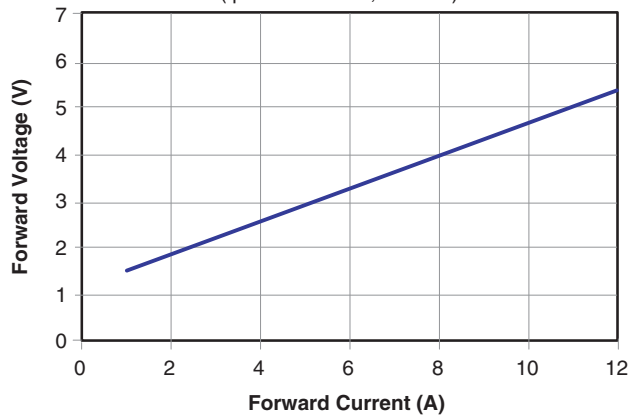
**Typical Variation of  $C_{IN}$  vs  $V_R$**   
( $f = 1\text{MHz}$ ,  $T = 25^\circ\text{C}$ )



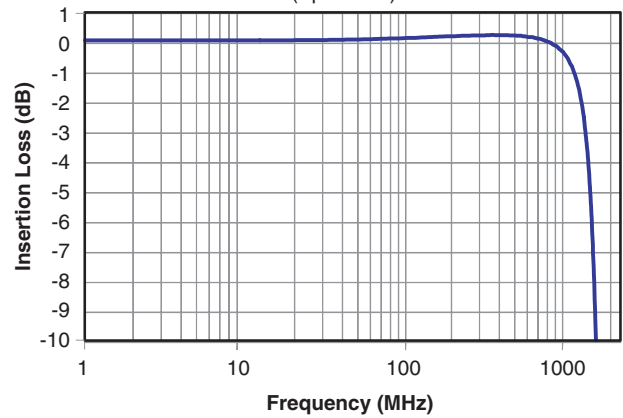
**Clamping Voltage vs. Peak Pulse Current**  
( $t_{\text{period}} = 100\text{ns}$ ,  $t_r = 1\text{ns}$ )



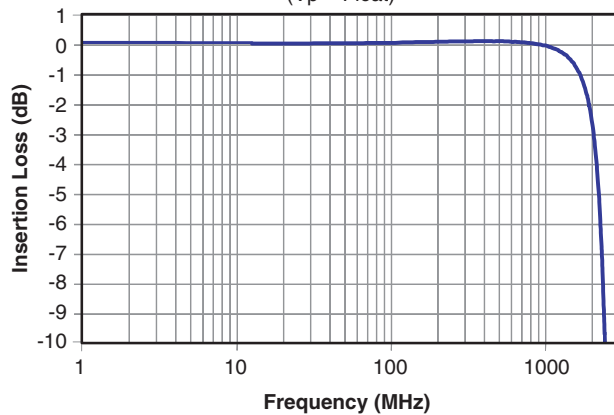
**Forward Voltage vs. Forward Current**  
( $t_{\text{period}} = 100\text{ns}$ ,  $t_r = 1\text{ns}$ )



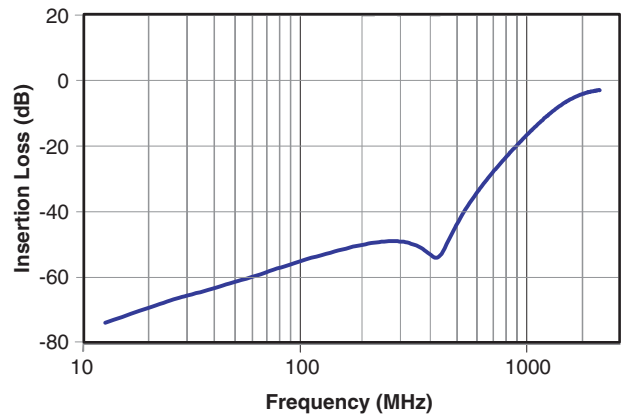
**I/O – Gnd Insertion Loss (S21) vs. Frequency**  
( $V_p = 3.3\text{V}$ )



**I/O – I/O Insertion Loss (S21) vs. Frequency**  
( $V_p = \text{Float}$ )



**Analog Crosstalk (I/O–I/O) vs. Frequency**



## Application Information

The AOZ8001 TVS is design to protect two data lines from fast damaging transient over-voltage by clamping it to a reference. When the transient on a protected data line exceed the reference voltage the steering diode is forward bias thus, conducting the harmful ESD transient away from the sensitive circuitry under protection.

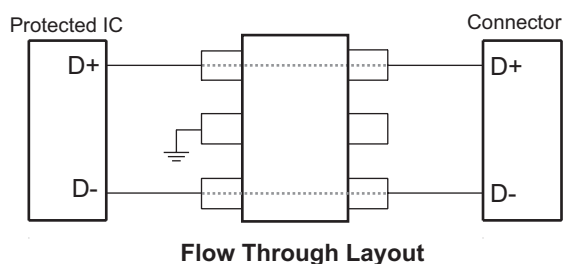
### PCB Layout Guidelines

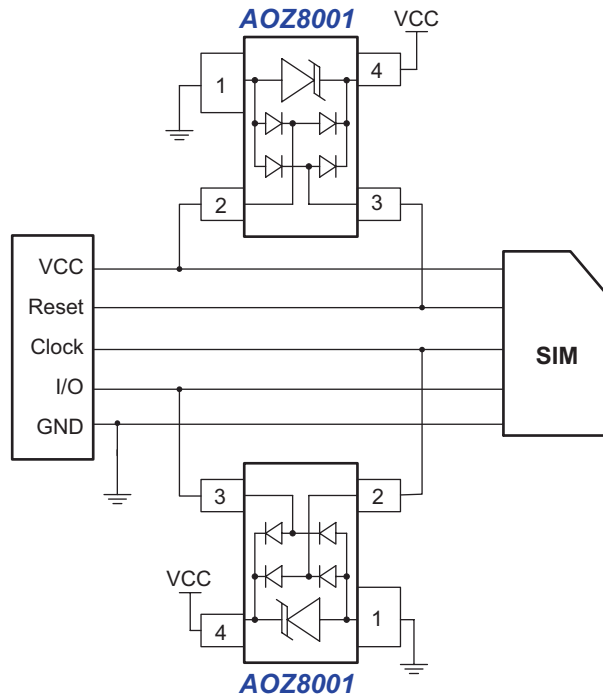
Printed circuit board layout is the key to achieving the highest level of surge immunity on power and data lines. The location of the protection devices on the PCB is the simplest and most important design rule to follow. The AOZ8001 devices should be located as close as possible to the noise source. The placement of the AOZ8001 devices should be used on all data and power lines that enter or exit the PCB at the I/O connector. In most systems, surge pulses occur on data and power lines that enter the PCB through the I/O connector. Placing the AOZ8001 devices as close as possible to the noise source ensures that a surge voltage will be clamped before the pulse can be coupled into adjacent PCB traces. In addition, the PCB should use the shortest possible traces. A short trace length equates to low impedance, which ensures that the surge energy will be dissipated by the AOZ8001 device. Long signal traces will act as antennas to receive energy from fields that are produced by the ESD pulse. By keeping line lengths as short as possible, the efficiency of the line to act as an antenna for ESD related fields is reduced. Minimize inter-connecting line lengths by placing devices with the most interconnect as close together as possible. The protection circuits should shunt the surge voltage to either the reference or chassis ground. Shunting the surge voltage directly to the IC's signal ground can cause ground bounce. The clamping performance of TVS diodes on a single ground PCB can be improved by minimizing the impedance with relatively short and wide ground traces. The PCB layout and IC package parasitic inductances can cause significant overshoot to the TVS's clamping voltage. The inductance of the PCB can be reduced by

using short trace lengths and multiple layers with separate ground and power planes. One effective method to minimize loop problems is to incorporate a ground plane in the PCB design. The AOZ8001 ultra-low capacitance TVS is designed to protect four high speed data transmission lines from transient over-voltages by clamping them to a fixed reference. The low inductance and construction minimizes voltage overshoot during high current surges. When the voltage on the protected line exceeds the reference voltage the internal steering diodes are forward biased, conducting the transient current away from the sensitive circuitry.

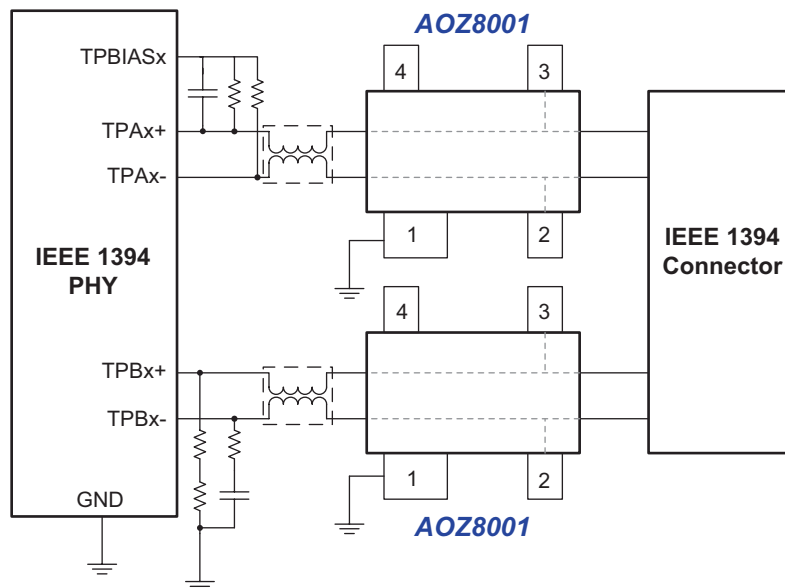
Good circuit board layout is critical for the suppression of ESD induced transients. The following guidelines are recommended:

1. Place the TVS near the IO terminals or connectors to restrict transient coupling.
2. Fill unused portions of the PCB with ground plane.
3. Minimize the path length between the TVS and the protected line.
4. Minimize all conductive loops including power and ground loops.
5. The ESD transient return path to ground should be kept as short as possible.
6. Never run critical signals near board edges.
7. Use ground planes whenever possible.
8. Avoid running critical signal traces (clocks, resets, etc.) near PCB edges.
9. Separate chassis ground traces from components and signal traces by at least 4mm.
10. Keep the chassis ground trace length-to-width ratio <5:1 to minimize inductance.
11. Protect all external connections with TVS diodes.

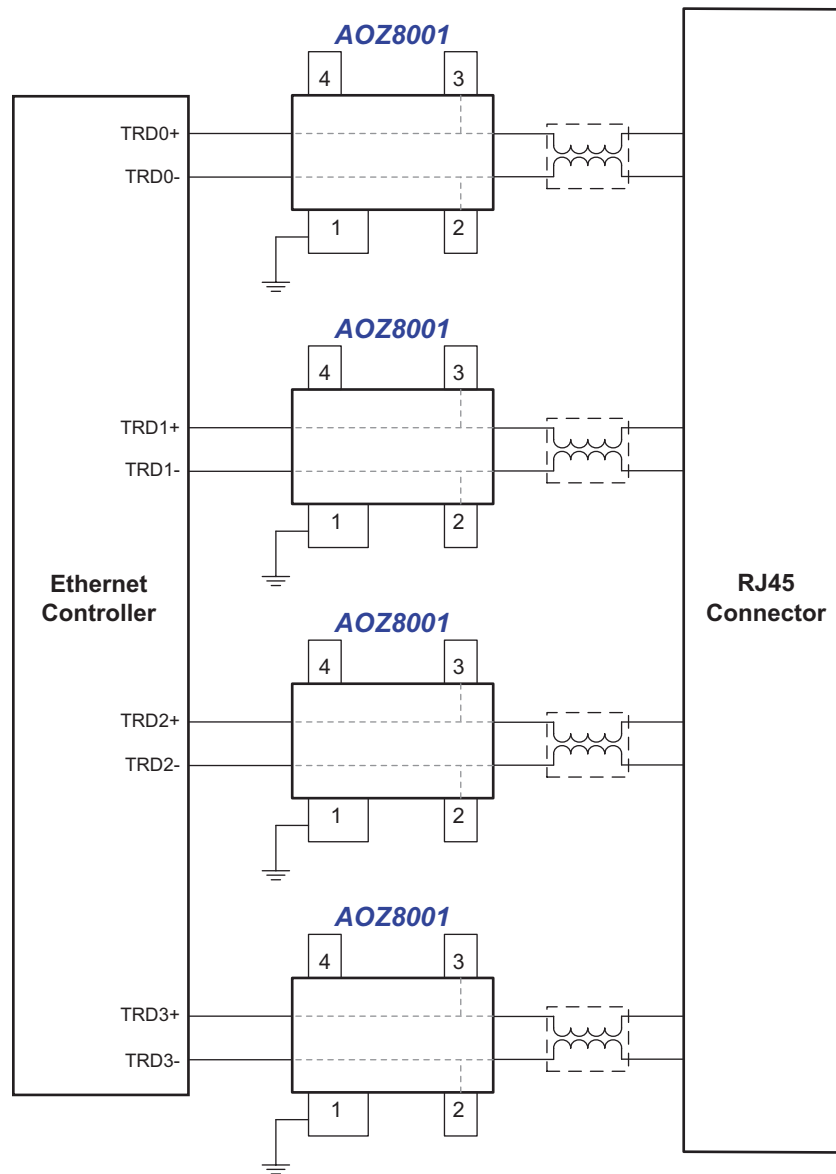




**SIM Card Port Connection**

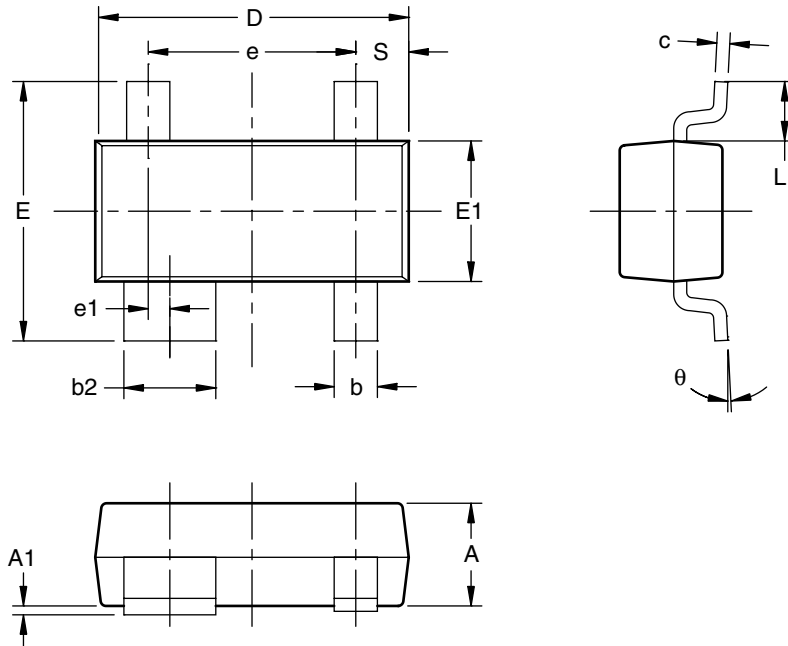


**IEEE1394 Port Connection**

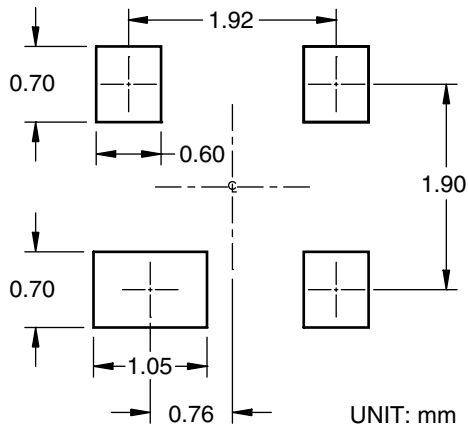


**10/100 Ethernet Port Connection**

## Package Dimensions, SOT143-4L



### RECOMMENDED LAND PATTERN



### Dimensions in millimeters

Symbols	Min.	Nom.	Max.
A	0.890	—	1.120
A1	0.013	—	0.100
b	0.370	—	0.510
b2	0.760	—	0.940
c	0.085	—	0.180
D	2.800	—	3.040
E	2.100	—	2.640
E1	1.200	—	1.400
e	1.920 BSC		
e1	0.200 BSC		
L1	0.550 REF		
S	0.450	—	0.600
θ	0°	—	8°

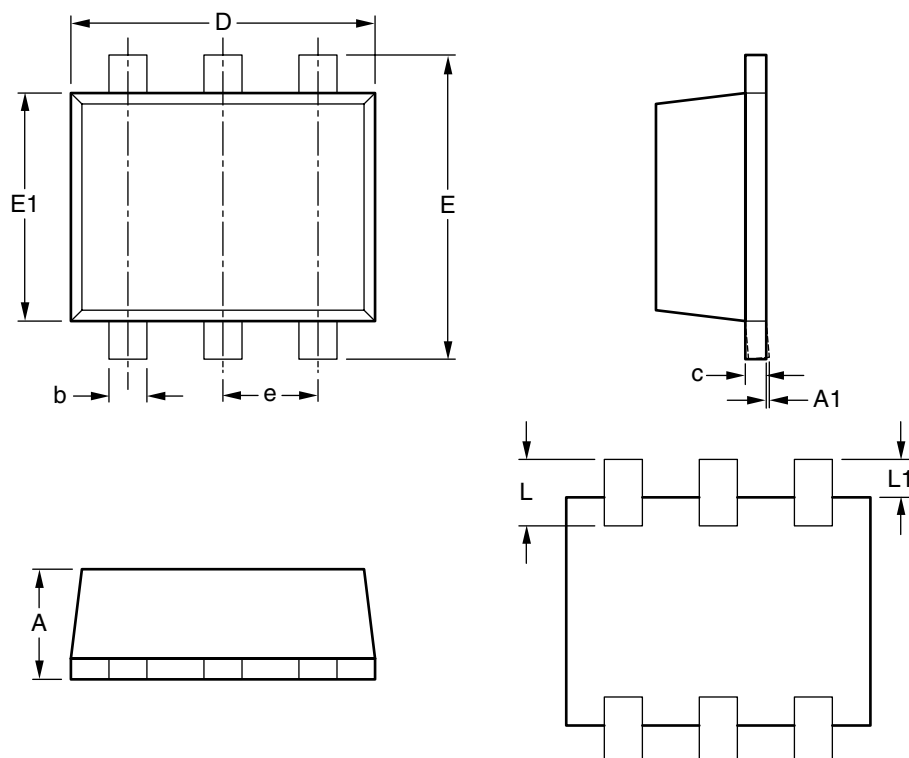
### Dimensions in inches

Symbols	Min.	Nom.	Max.
A	0.035	—	0.044
A1	0.001	—	0.004
b	0.015	—	0.020
b2	0.030	—	0.037
c	0.003	—	0.007
D	0.110	—	0.120
E	0.083	—	0.104
E1	0.047	—	0.055
e	0.076 BSC		
e1	0.008 BSC		
L1	0.022 REF		
S	0.018	—	0.024
θ	0°	—	8°

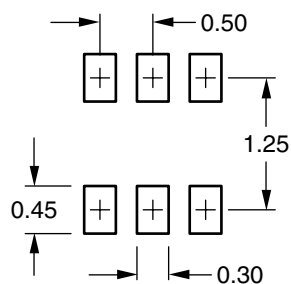
### Notes:

1. All dimensions are in millimeters.
2. Tolerances are 0.10mm unless otherwise specified.
3. Package body sizes exclude mold flash and gate burrs.
4. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.

## Package Dimensions, SC-89



### RECOMMENDED LAND PATTERN



UNIT: mm

### Dimensions in millimeters

Symbols	Min.	Nom.	Max.
A	0.53	0.58	0.62
A1	0.00	—	0.10
b	0.15	0.20	0.30
c	0.10	0.11	0.18
D	1.50	1.60	1.70
E	1.50	1.60	1.70
E1	1.10	1.20	1.30
e	0.50 BSC		
L	0.25	0.35	0.45
L1	0.13	0.20	0.27

### Dimensions in inches

Symbols	Min.	Nom.	Max.
A	0.021	0.023	0.024
A1	0.000	—	0.004
b	0.006	0.008	0.012
c	0.004	0.004	0.007
D	0.059	0.063	0.067
E	0.059	0.063	0.067
E1	0.043	0.047	0.051
e	0.020 BSC		
L	0.010	0.014	0.018
L1	0.005	0.008	0.011

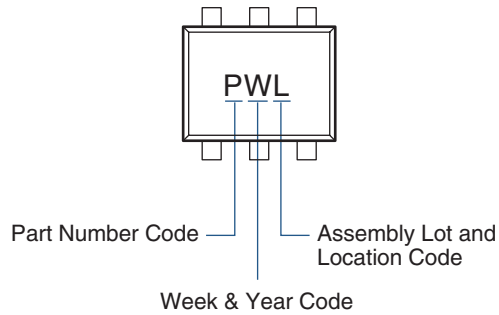
### Notes:

1. Dimension D does not include mold flash, protrusions or gate burrs. Mold flash, protrusions or gate burrs shall not exceed 0.15mm per end. Dimension E1 does not include interlead flash or protrusion.
2. Dimensions D and E1 are determined at the outmost extremes of the plastic body exclusive of mold flash, tie bar burrs, gate burrs and interlead flash, but including any mismatch between the top and bottom of the plastic body.
3. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.
4. All dimensions are in millimeters.



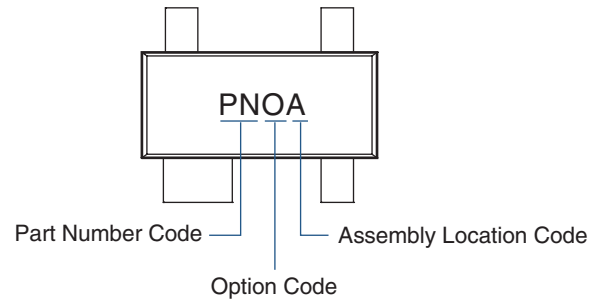
## Part Marking

**AOZ8001KI  
(SC-89)**

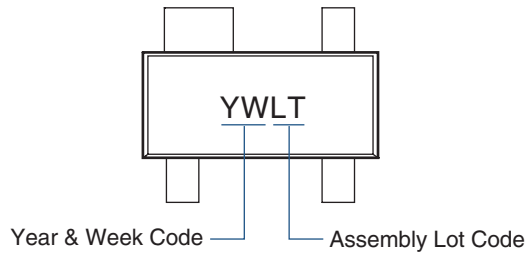


**AOZ8001JI  
(SOT-143)**

### Top Marking



### Bottom Marking



**This datasheet contains preliminary data; supplementary data may be published at a later date. Alpha & Omega Semiconductor reserves the right to make changes at any time without notice.**

#### LIFE SUPPORT POLICY

ALPHA & OMEGA SEMICONDUCTOR PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS.

As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
2. A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.